

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10625567	FUNAKOSHI ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	NHAN T TRAN	2622

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
348	241	3/13/2007	NT
358	463	3/15/2007	NT
348	229.1	3/15/2007	NT
348	242, 243, 248	7/7/2008	NT

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	3/13/2007	NT
348/241-251 (text search)	3/13/2007	NT
382/167 (text search)	3/15/2007	NT
348, 273-283, 222.1, 606, 607, 627 (text search)	3/15/2007	NT
Text search for all classes	3/15/2007	NT
Inventorship search	3/15/2007	NT
348/223.1, 257 (text search)	6/30/2008	NT
Updated text search for all classes	7/2/2008	NT

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
ALL	PGPUB text search	7/7/2008	NT